Colorado School of Mines
Office for Technology Transfer

Novel Photoconductive Decay Measurement System

Drs. Richard Ahrenkiel and Donald Dunlavy

Department of Metallurgical and Material Engineering

Description: This invention provides a nondestructive, contactless means to measure the recombination of lifetime of a wide range of semiconducting and photoconducting materials. The device exceeds the performance and range of applicability of existing commercial products. It utilizes a novel system of radio frequency coils that allow for rapid data acquisition time with no contact of the sensitive photovoltaic material.

Potential Areas of Application

- Photovoltaic industry
- Microelectronic industry
- Optoelectronic industry

Main Advantages of this Invention

- Fast data acquisition time.
- Provides a non-destructive means of measuring the lifetime of a variety of materials
- Performance exceeds those of current methods
- Has a greater range of applicability than the current method

Intellectual Property Status: Provisional patent filing pending

ID number: 09001

Opportunity: We are seeking an exclusive or non-exclusive licensee for marketing, manufacturing, and sale of this technology.

Contact

William Vaughan
Director, Technology Transfer
Colorado School of Mines
1500 Illinois Street
Guggenheim Hall, Suite 314
Golden, CO 80401
Phone: 303.384.2555
Fax: 303.273.3244
Email: wvaughan@mines.edu